## Power MOSFET

## 30 V, 65 A, Single N-Channel, SO-8 FL

#### **Features**

- Integrated Schottky Diode
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free and are RoHS Compliant

## **Applications**

- CPU Power Delivery
- Synchronous Rectification for DC-DC Converters
- Low Side Switching
- Telecom Secondary Side Rectification

## **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Volt	Drain-to-Source Voltage			30	V
Gate-to-Source Volta	age		V <sub>DSS</sub> V <sub>GS</sub>	±20	V
Continuous Drain Current R <sub>0JA</sub>		T <sub>A</sub> = 25°C	I <sub>D</sub>	23.9	Α
(Note 1)		T <sub>A</sub> = 85°C		17.2	
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C	$P_{D}$	3.04	W
Continuous Drain Current $R_{\theta JA} \leq$		T <sub>A</sub> = 25°C	I <sub>D</sub>	36	Α
10 sec		T <sub>A</sub> = 85°C		26	
Power Dissipation $R_{\theta JA,} t \leq 10 \text{ sec}$	Steady	T <sub>A</sub> = 25°C	$P_{D}$	7.0	W
Continuous Drain Current R <sub>0JA</sub>	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	17.5	Α
(Note 2)		T <sub>A</sub> = 85°C		12.6	
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C	$P_{D}$	1.63	W
Continuous Drain Current R <sub>BJC</sub>		$T_C = 25^{\circ}C$	I <sub>D</sub>	65	Α
(Note 1)		T <sub>C</sub> = 85°C		47	
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C	$P_{D}$	22.73	W
Pulsed Drain Current	t <sub>p</sub> =10μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	195	Α
Current limited by page	ckage	T <sub>A</sub> = 25°C	I <sub>Dmaxpkg</sub>	100	Α
Operating Junction as Temperature	Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Source Current (Body Diode)		I <sub>S</sub>	64	Α	
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 50 V, $V_{GS}$ = 10 V, $I_{L}$ = 33 $A_{pk}$ , $L$ = 0.1 mH, $R_{G}$ = 25 $\Omega$ )		EAS	54	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

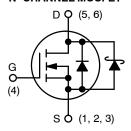


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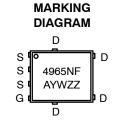
## http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	3.4 m $\Omega$ @ 10 V	GE A
30 V	5.0 mΩ @ 4.5 V	65 A

## **N-CHANNEL MOSFET**







4965NF = Specific Device Code A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4965NFT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4965NFT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	5.5	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	41.15	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	76.9	C/VV
Junction-to-Ambient - t ≤ 10 sec	$R_{ heta JA}$	17.86	

- Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size of 100 mm<sup>2</sup>.

## **ELECTRICAL CHARACTERISTICS** (T<sub>.I</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condi	tion	Min	Тур	Max	Unit
OFF CHARACTERISTICS				ı	1		
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 1.0 \text{ mA}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>	I <sub>D</sub> = 10 mA, referenced to 25°C			15		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25°C			500	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$				±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 1.0 \text{ mA}$		1.2	1.6	2.3	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	I <sub>D</sub> = 10 mA, referen	ced to 25°C		5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		2.7	3.4	
			I <sub>D</sub> = 15 A		2.7		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		4.0	5.0	mΩ
			I <sub>D</sub> = 15 A		4.0		1
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			43		S
CHARGES AND CAPACITANCES					•		
Input Capacitance	C <sub>ISS</sub>				2100		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			900		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				60		
Total Gate Charge	Q <sub>G(TOT)</sub>				14.2		-
Threshold Gate Charge	Q <sub>G(TH)</sub>	.,	51/ L 00 A		1.8		
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			5.9		nC
Gate-to-Drain Charge	$Q_{GD}$				4.2		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A			30.5		nC
SWITCHING CHARACTERISTICS (Note 4)	-			-	<u>-</u>	-	-
Turn-On Delay Time	t <sub>d(ON)</sub>				11		
Rise Time	t <sub>r</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			32		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				21		
Fall Time	t <sub>f</sub>				6.0		

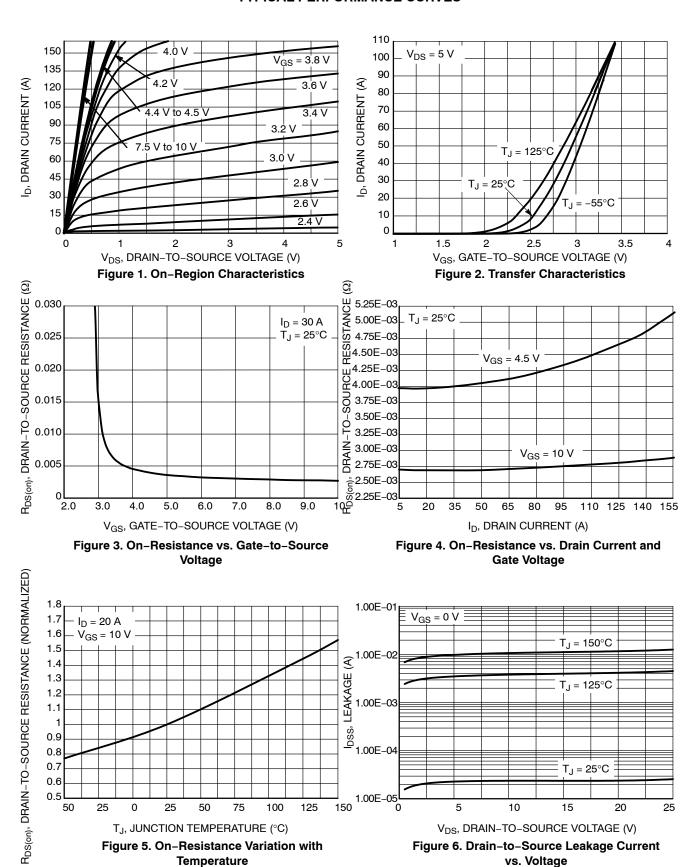
- 3. Pulse Test: pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2%.
- 4. Switching characteristics are independent of operating junction temperatures.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)						
Turn-On Delay Time	t <sub>d(ON)</sub>			8.5		- ns	
Rise Time	t <sub>r</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			26.5		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				26		
Fall Time	t <sub>f</sub>				4.5		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2 A	$T_J = 25^{\circ}C$		0.4	0.7	
			T <sub>J</sub> = 125°C		0.33		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_S/dt = 100 \text{ A/}\mu\text{s,}$ $I_S = 2 \text{ A}$			36.5		ns
Charge Time	t <sub>a</sub>				18		
Discharge Time	t <sub>b</sub>				18.5		
Reverse Recovery Charge	Q <sub>RR</sub>				32		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.65		nH
Drain Inductance	L <sub>D</sub>				0.20		1
Gate Inductance	L <sub>G</sub>				1.5		
Gate Resistance	$R_{G}$				1.0		Ω

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

## **TYPICAL PERFORMANCE CURVES**



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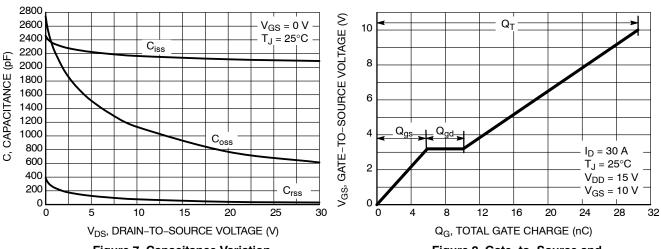


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

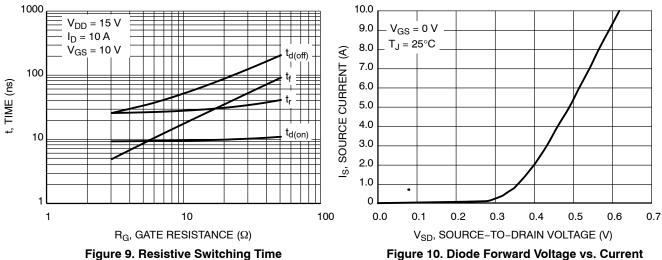


Figure 9. Resistive Switching Time

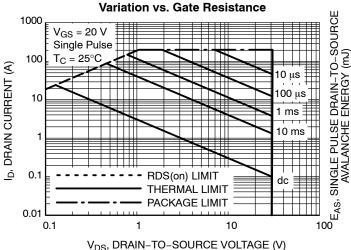
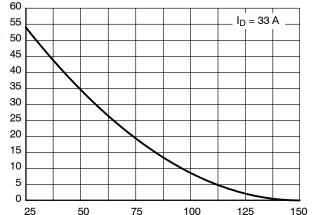


Figure 11. Maximum Rated Forward Biased Safe Operating Area



T<sub>J</sub>, STARTING JUNCTION TEMPERATURE (°C)

Figure 12. Maximum Avalanche Energy vs. **Starting Junction Temperature** 

## **TYPICAL PERFORMANCE CURVES**

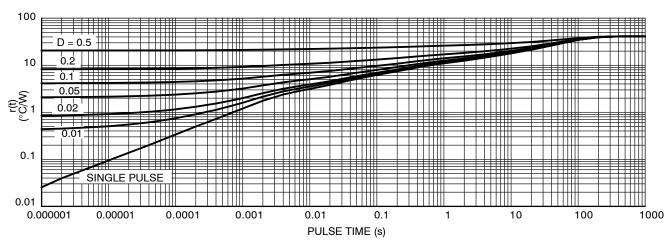
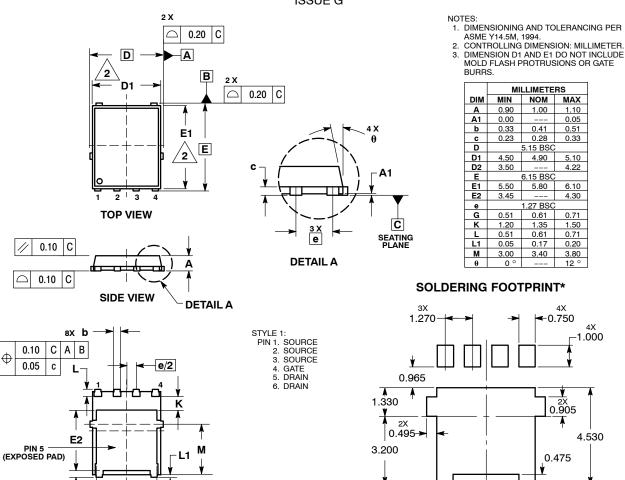


Figure 13. Thermal Response

#### PACKAGE DIMENSIONS

# **DFN5 5x6, 1.27P (SO8 FL)**CASE 488AA ISSUE G



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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